Se	earch No	res

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/766,005	TANAKA, SHINJI	
Examiner	Art Unit	
Jordany Múñoz	2170	

SEARCHED				
Class	Subclass	Date	Examiner	
715	722	8/14/2006	JN	
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
		 	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
East: USPAT, US PGPUB, EPO, JPO, Derwent, IBM-IDB	8/14/2006	JN	
NPL	8/14/2006	И	
Consulted with primary examiner, Ba Huynh, AU 2179	8/14/2006	ИС	
Search updated	1/2/07	12	
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